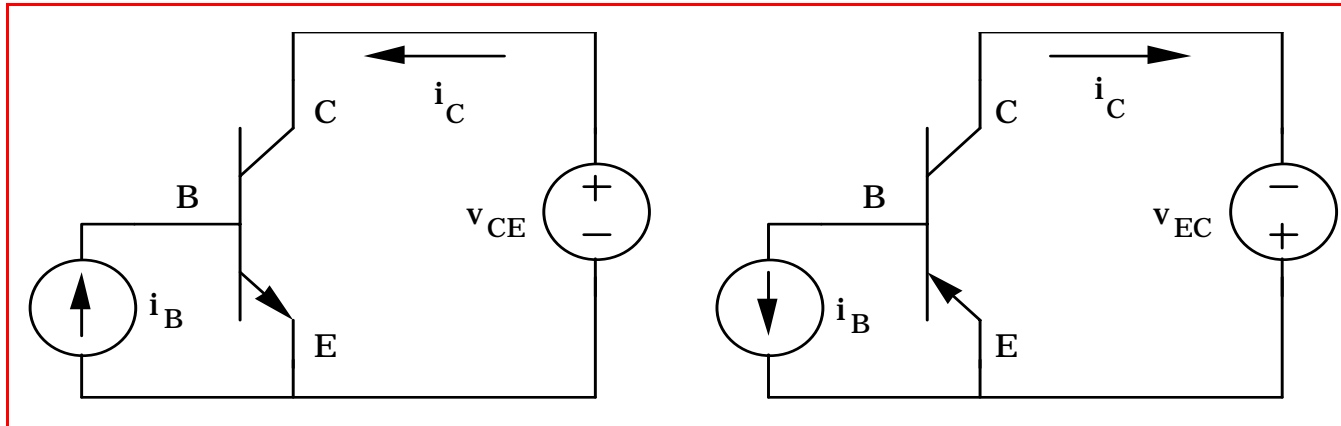
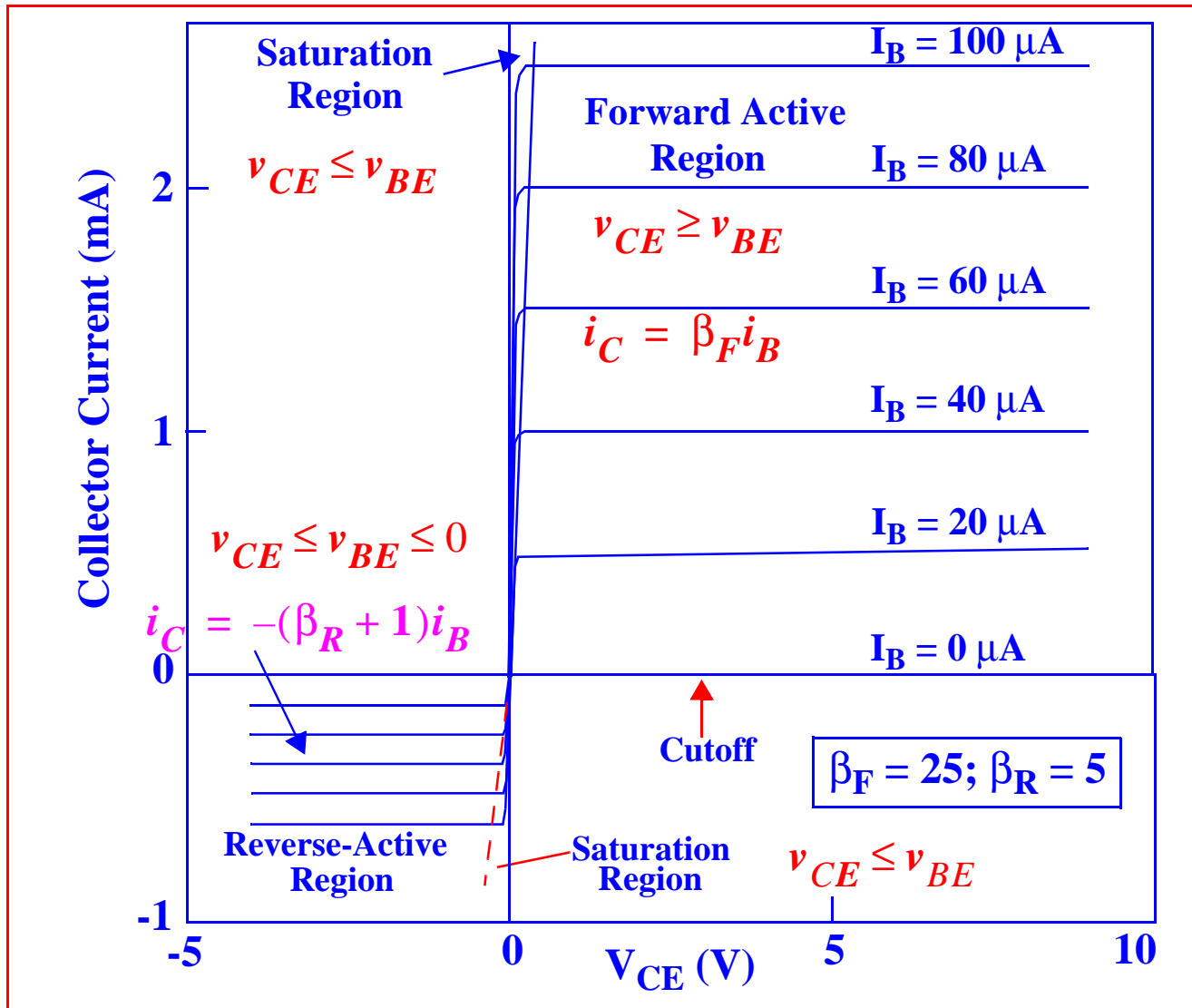


# I-V Characteristics of BJT

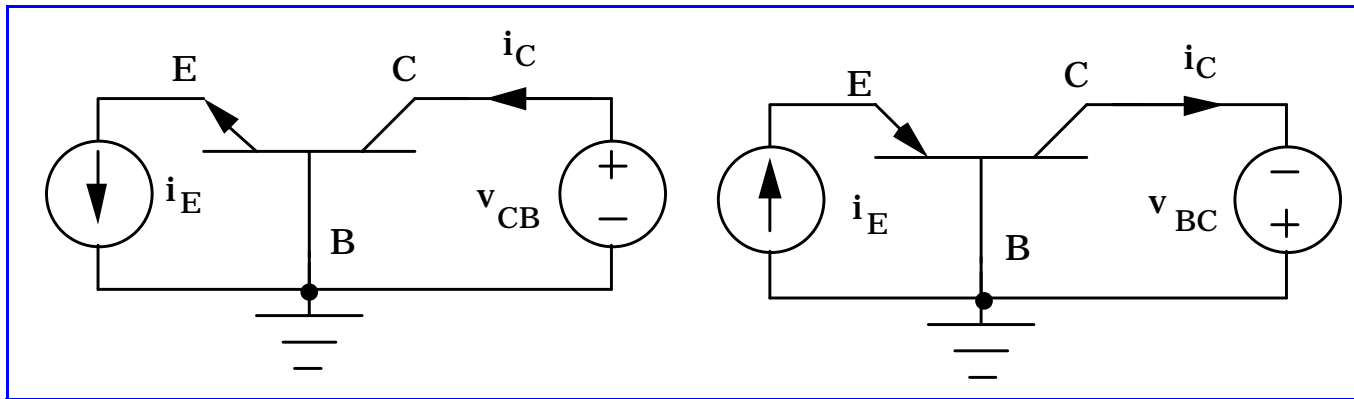
## Common-Emitter Output Characteristics

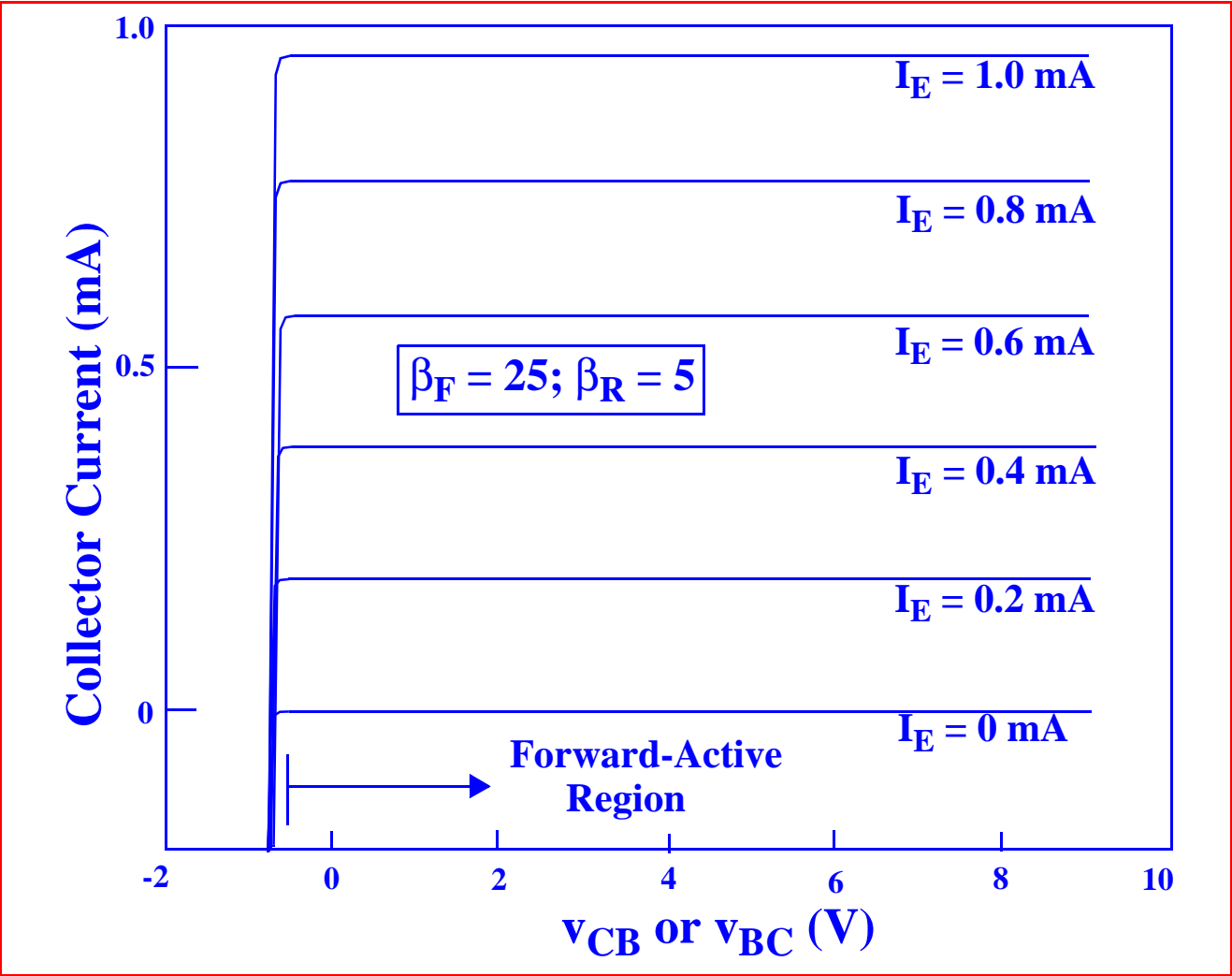


To illustrate the  $I_C$ - $V_{CE}$  characteristics, we use an enlarged  $\beta_R$



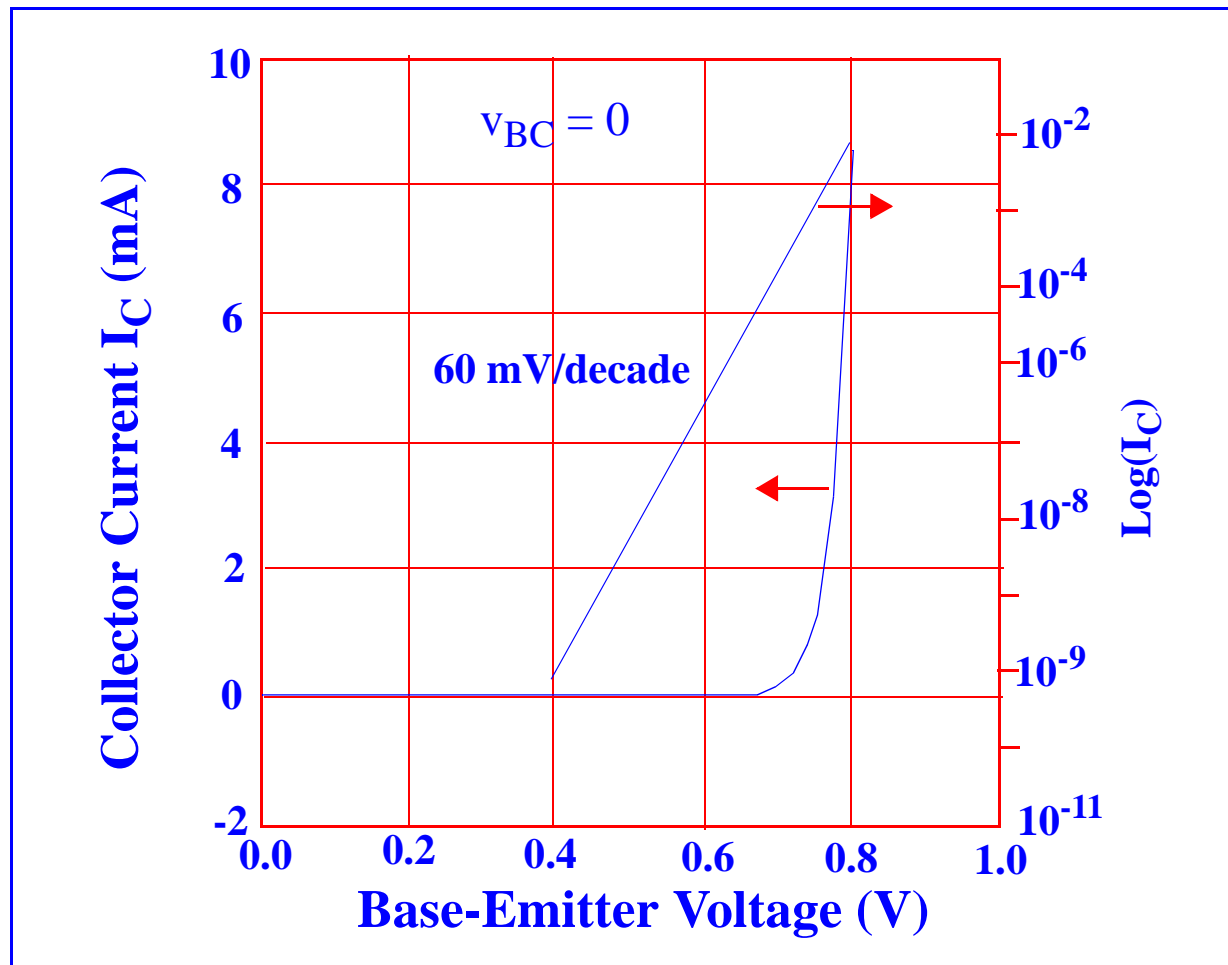
## Common Base Output Characteristics





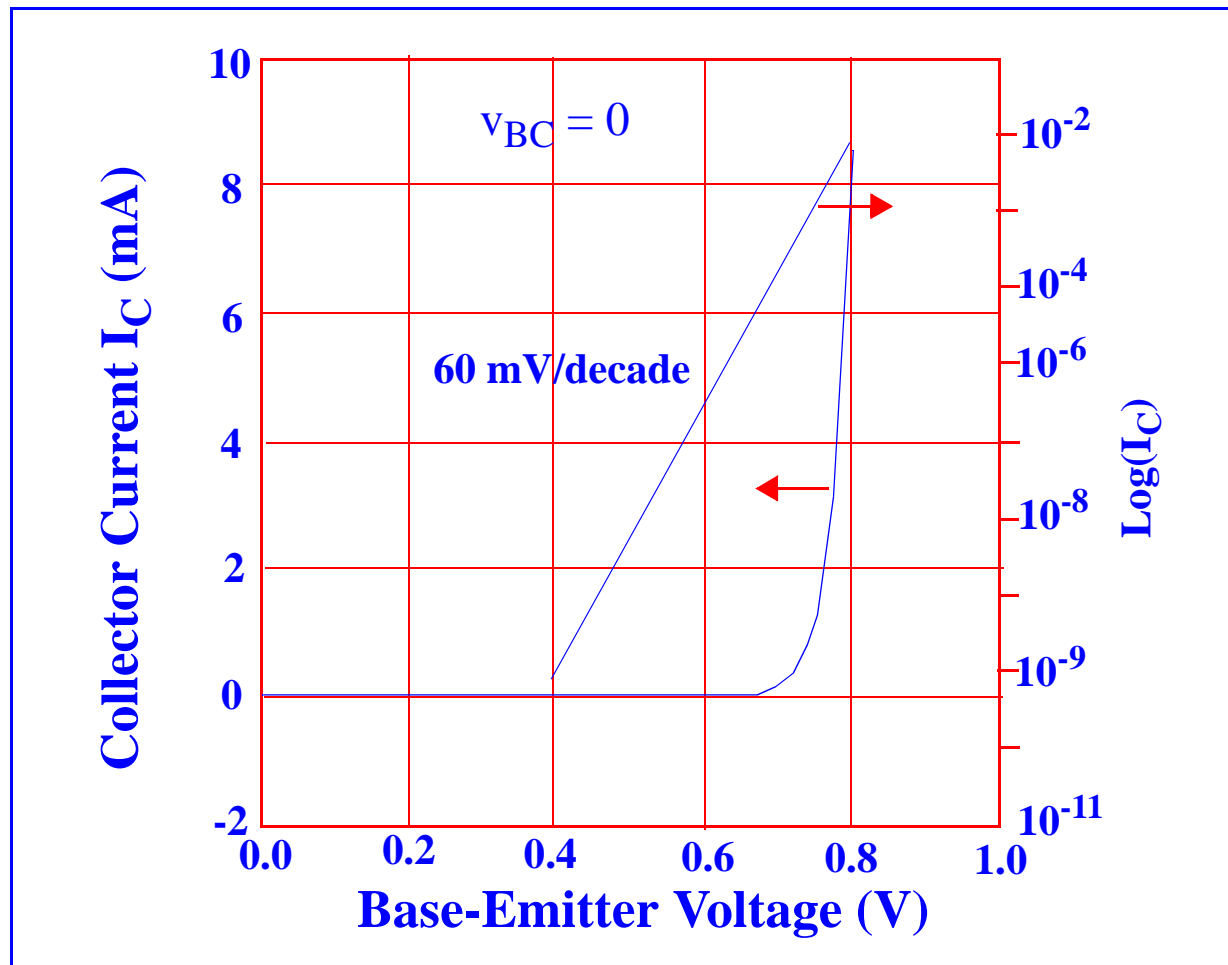
## Common-Emitter Transfer Characteristic $i_C - v_{BE}$

- . BE voltage changes as  $-1.8 \text{ mV}/^\circ\text{C}$  - this is its temperature coefficient (recall from diodes).



## Common-Emitter Transfer Characteristic $i_C - v_{BE}$ (p. 180)

$$I_C = I_S \left\{ \exp\left(\frac{v_{BE}}{V_T}\right) - 1 \right\}. \text{ BE voltage changes as } -1.8 \text{ mV}/^\circ\text{C} \text{ - this is its temperature coefficient (recall from diodes).}$$



**Junction Breakdown** - BJT has two diodes back-to-back. Each diode has a breakdown. The diode (BE) with higher doping concentrations has the lower breakdown voltage (5 to 10 V).

In **forward active region**  $V_{BC}$  junction is reverse biased.

In **cut-off region**,  $V_{BE}$  and  $V_{BC}$  are both reverse biased.

The transistor must withstand these reverse bias voltages.

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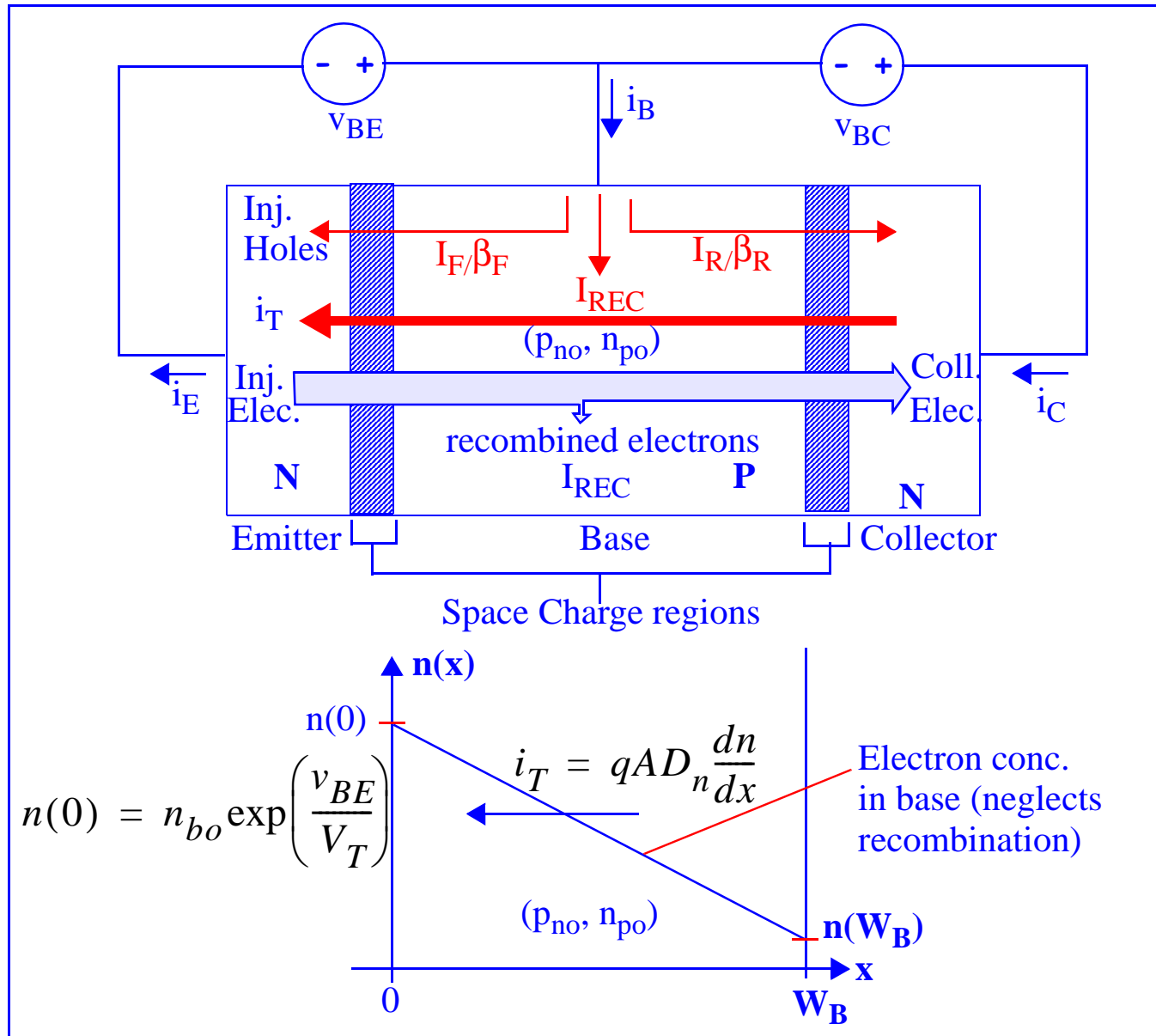
**Junction Breakdown** - BJT has two diodes back-to-back. Each diode has a breakdown. The diode (BE) with higher doping concentrations has the lower breakdown voltage (5 to 10 V).

In **forward active region**, BC junction is reverse biased.

In **cut-off region**, BE and BC are both reverse biased.

The transistor must withstand these reverse bias voltages.

# Minority Carrier Transport in Base Region



Transport current  $i_T$  results from diffusion of minority carriers (holes in npn) across base region.

Base current  $i_B$  is composed of holes injected back into E and C and  $I_{REC}$  needed to replenish holes lost to recombination with electrons in B.

The minority carrier concentrations at two ends of base are

and

where  $n_{b0}$  is the equilib-

rium electron density in the base region.

The junction voltages establish a minority carrier concentration gradient at ends of base region. For a narrow base, we get

$W_B$  is the B width;  $A$  is the cross-sectional area of B region.

The saturation current is

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Base current  $i_B$  is composed of holes injected back into E and C and  $I_{REC}$  needed to replenish holes lost to recombination with electrons in B.

The minority carrier concentrations at two ends of base are

$n(0) = n_{bo} \exp\left(\frac{v_{BE}}{V_T}\right)$  and  $n(W_B) = n_{bo} \exp\left(\frac{v_{BC}}{V_T}\right)$  where  $n_{bo}$  is the equilibrium electron density in the base region.

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$$i_T = \left| qAD_n \frac{dn}{dx} \right| = \left| -qAD_n \frac{n_{bo}}{W_B} \left\{ \exp\left(\frac{v_{BE}}{V_T}\right) - \exp\left(\frac{v_{BC}}{V_T}\right) \right\} \right|.$$

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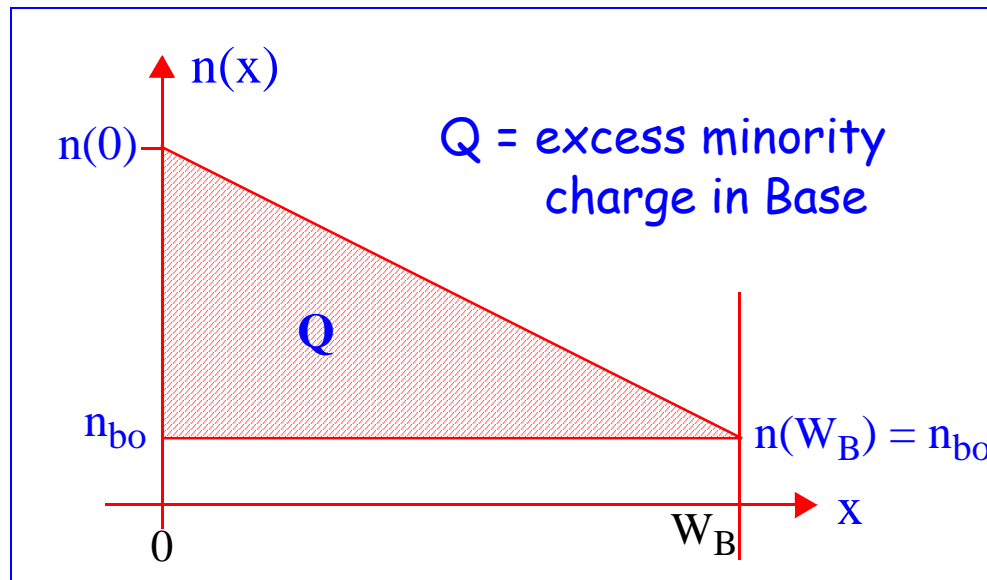
The saturation current is 
$$I_S = qAD_n \frac{n_{bo}}{W_B} = qAD_n \frac{n_i^2}{N_{AB} W_B}.$$

## Base Transit Time

Forward transit time is time associated with storing charge  $Q$  in Base region and it is

$$\tau_F = \frac{Q}{i_T} \quad \text{with} \quad Q = qA[n(0) - n_{bo}] \frac{W_B}{2} .$$

Using  $Q = qAn_{bo} \left\{ \exp\left(\frac{v_{BE}}{V_T}\right) - 1 \right\} \frac{W_B}{2}$  we get

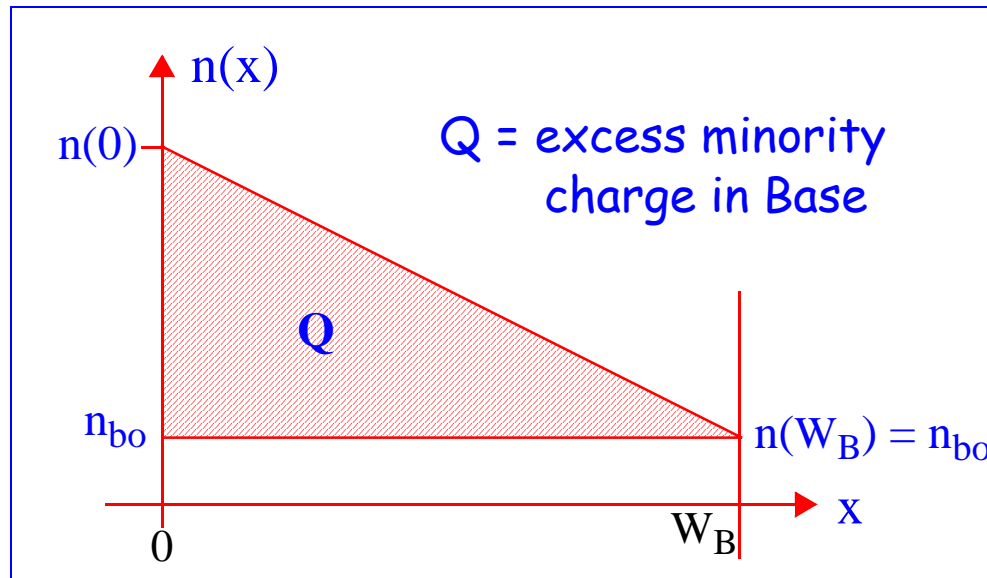


Using  $Q = qAn_{bo} \left\{ \exp\left(\frac{v_{BE}}{V_T}\right) - 1 \right\} \frac{W_B}{2}$  we get

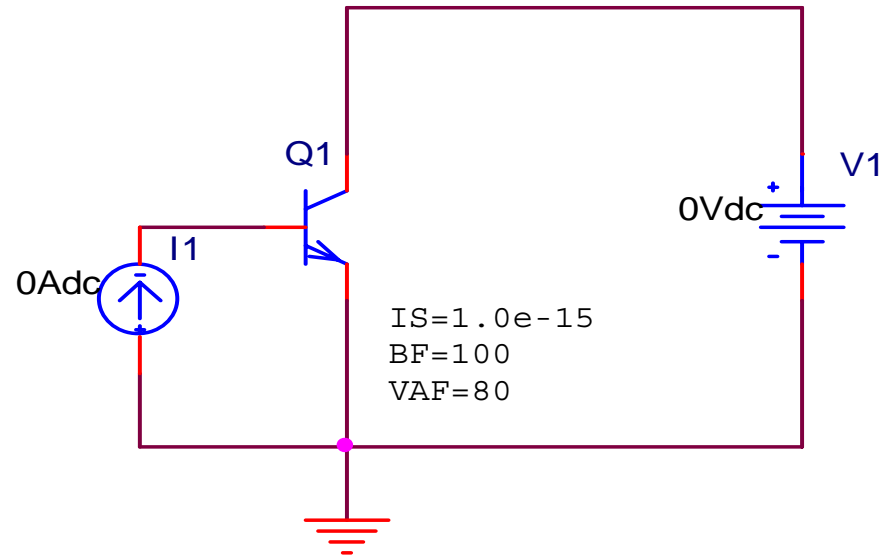
$$i_T = \frac{qAD_n}{W_B} n_{bo} \left\{ \exp\left(\frac{v_{BE}}{V_T}\right) - 1 \right\} \quad \text{and} \quad \tau_F = \frac{W_B^2}{2D_n} = \frac{W_B^2}{2V_T \mu_n} .$$



This defines an upper limit on frequency  $f \leq \frac{1}{2\pi\tau_F}$ .



# PSPICE EXAMPLE



**\*Libraries:**

**\* Local Libraries :**

**.LIB ".\example10.lib"**

**\* From [PSPICE NETLIST] section of C:\Program Files\OrCAD\PSpice\PSpice.ini file:**

**.lib "nom.lib"**

**\*Analysis directives:**

**.DC LIN V\_V1 0 5 0.05**

**+ LIN I\_I1 10u 100u 10u**

**.PROBE V(\*) I(\*) W(\*) D(\*) NOISE(\*)**

**.INC ".\example10-SCHEMATIC1.net"**

**\*\*\*\* INCLUDING example10-SCHEMATIC1.net \*\*\*\***

**\* source EXAMPLE10**

## PSPICE EXAMPLE (Cont'd)

Q\_Q1        N00060 N00159 0 Qbreakn

V\_V1        N00060 0 0Vdc

I\_I1        0 N00159 DC 0Adc

\*\*\*\* RESUMING example10-SCHEMATIC1-Example10Profile.sim.cir \*\*\*\*

.END

\*\*\*\*        BJT MODEL PARAMETERS

\*\*\*\*\*

Qbreakn

NPN

IS    1.000000E-15

BF    100

NF    1

VAF    80

BR    3

NR    1

VAR    30

CN    2.42

D     .87

JOB CONCLUDED

TOTAL JOB TIME                    .21

# PSPICE EXAMPLE (Cont'd)

